

Special Issue

Recent Advances in Electromagnetic Non- destructive Testing and Evaluation

Message from the Guest Editor

Electromagnetic sensors can be employed as a means for defect detection within non-destructive testing, representing a technique that can be applied to the aircraft, aerospace, and rail industries. In recent years, there have been various new developments in this field, such as in sensor design, instrument development, new algorithms, and different applications. This Special Issue of *NDT* on “Recent Advances in Electromagnetic Non-destructive Testing and Evaluation” welcomes contributions based on the following topics:

- Defect detection using electromagnetic techniques;
- Electromagnetic sensor design and instrumentation;
- Novel electromagnetic NDT;
- Advanced signal and image processing;
- Condition monitoring.

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